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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.

: National Phase Entry of PCT/EP2004/006314

Applicant

: MASSELINK et al

Filed

: January 31, 2006

TC/A.U.

Examiner

: 3367-101

Customer No.

Docket No.

0440

Confirmation No.

: 6449

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

In compliance with applicants duty of disclosure under 37 C.F.R. 1.56, enclosed is a copy of the International Search Report in the corresponding international application. The relevance of the references is noted in the International Search Report. We understand that the references have been forwarded by the International Bureau, and are available to the Examiner, but if the Examiner needs copies of any of the references, the Examiner is requested to advise counsel accordingly. Also listed on the 1449 are references that are known to the applicant. Also enclosed is an English translation of an office action in the corresponding German priority application and, the cited references are also listed on the attached 1449. A copy of all of the non-US patent references will follow.

In the event that any fees are due with this paper, please charge our Deposit Account No. 02-2135.

Respectfully submitted,

By .

Robert B. Murray

Attorney for Applicant

Registration No. 22,980

ROTHWELL, FIGG, ERNST & MANBECK

1425 K. Street, Suite 800 Washington, D.C. 20005

Telephone: (202) 783-6040

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				Complete if Known				
				Application Number	New Application 31			
INFORMA [*]				Filing Date	January 31, 2006			
STATEME	NI BY AP	PLICAI	NI	First Named Inventor	MASSELINK et al			
				Group Art Unit				
				Examiner Name				
				Confirmation No.				
Sheet 1 of 4		Attorney Docket Number	3367-101					

	U.S. PATENT DOCUMENTS								
Examiner Initials*	Cite No.1	U.S. Patent Document Number Kind Code ² (if known)		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY				
	1.	2002/162995	A1	Horguchi Naoto NMI et al	11/7/02				
	2.	2003/052317	A1	Ohshima Toshio	3/20/03				
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code. ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.

Michael Terror 31 Jan 2006

				Complete if Known		
				Application Number	New Applications 1	
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STATEMI	ENT BY AP	PLICAI	NΤ	First Named Inventor	MASSELINK et al	
				Group Art Unit		
				Examiner Name		
				Confirmation No.		
Sheet	2	of	4	Attorney Docket Number	3367-101	

			FOR	REIGN PA	TENT DOCUMEN	TS		
Examiner	Cite		Foreign Patent Docur		Name of Patent	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document	
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Examiner Signature		/	L Matthew Reames	/ /		Date Considered	09/24/2008	<u> </u>

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code. ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁴Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.

Receipt date: 01/31/2006

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				Application Number	New Capplicate of 1	
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				Group Art Unit		
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				Confirmation No.		
Sheet	3	of	4	Attorney Docket Number	3367-101	

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T²
	12.	Mikhailov SA., "A New Type of Tunable Solid-State Far-Infared Lasers", CONF LASERS ELECTRO OPT EUR TECH DIG, 14 September 1998, pg. 92	
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Examiner		Date	09/24/2008
Signature	/Matthew Reames/	Considered	

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1 Unique citation designation number. 2 Applicant is to place a check mark here if English language Translation is attached.